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# **Dual N-Channel 60 V (D-S) MOSFET**

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>d</sup>	Q <sub>g</sub> (Typ.)		
60	0.0155 at V <sub>GS</sub> = 10 V	12	28 nC		
	0.0186 at V <sub>GS</sub> = 4.5 V	10	20110		

#### **FEATURES**

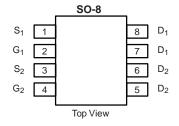
- DT-Trench Power MOSFET
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested

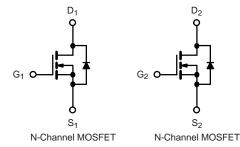


RoHS COMPLIANT

#### **APPLICATIONS**

• System power DC/DC





PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-source voltage		$V_{DS}$	60	V	
Gate-source voltage		$V_{GS}$	± 20		
	T <sub>C</sub> = 25 °C		12ª		
Continuous dusin surrent (T. 150 °C)	T <sub>C</sub> = 70 °C	Ι , Γ	10 <sup>a</sup>	A	
Continuous drain current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	7 <sup>a</sup>		
	T <sub>A</sub> = 70 °C	1	4.1 <sup>a</sup>		
Pulsed drain current		I <sub>DM</sub>	48		
Source-drain current diode current	T <sub>C</sub> = 25 °C		12		
	T <sub>A</sub> = 25 °C	ls –	2.8 b, c		
Maximum power dissipation	T <sub>C</sub> = 25 °C		22	w	
	T <sub>C</sub> = 70 °C	]	15		
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.3 b, c		
	T <sub>A</sub> = 70 °C		1.6 <sup>b, c</sup>		
Operating junction and storage temperature range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Soldering recommendations (peak temperature)			260		

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	TYP.	MAX.	UNIT	
Maximum junction-to-ambient b, d	ximum junction-to-ambient $b, d$ $t \le 10 s$		22	40	°C/W	
Maximum junction-to-case (drain)	Steady state	R <sub>thJC</sub> 3.5 6		C/VV		

#### Notes

- a. Package limited
- b. Surface mounted on 1" x 1" FR4 board
- c. t = 10 s
- d. Maximum under steady state conditions is 80 °C/W

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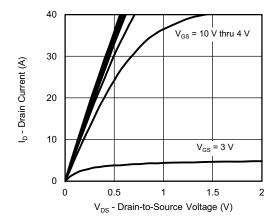
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static				•			
Drain-source breakdown voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60	-	-	V	
V <sub>DS</sub> temperature coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA	-	38	-		
V <sub>GS(th)</sub> temperature coefficient	ΔV <sub>GS(th)</sub> /T <sub>J</sub>	I <sub>D</sub> = 250 μA	-	-4.9	-	mV/°C	
Gate threshold voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0	-	3.0	V	
Gate-body leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	100	nA	
7	I <sub>DSS</sub>	V <sub>DS</sub> = 48 V, V <sub>GS</sub> = 0 V	-	-	1		
Zero gate voltage drain current		V <sub>DS</sub> = 48 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 85 °C	-	-	10	μA	
On-state drain current <sup>b</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	12	-	-	Α	
D		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8 A	-	0.0155	0.020	Ω	
Drain-source on-state resistance b	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 6 \text{ A}$	-	0.0186	0.025		
Forward transconductance <sup>b</sup>	9 <sub>fs</sub>	$V_{DS} = 30 \text{ V}, I_D = 8 \text{ A}$	-	38	-	S	
Dynamic <sup>a</sup>							
Input capacitance	C <sub>iss</sub>		-	4550	-	pF	
Output capacitance	C <sub>oss</sub>	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	365	-		
Reverse transfer capacitance	C <sub>rss</sub>		-	21	-		
Tabalanda alama	Q <sub>g</sub>	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	-	28	-	nC	
Total gate charge			-	8.3	-		
Gate-source charge	Q <sub>qs</sub>	$V_{DS} = 30 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 6 \text{ A}$	-	3.7	-		
Gate-drain charge	Q <sub>ad</sub>		-	1.5	-		
Gate resistance	R <sub>q</sub>	f = 1 MHz	-	5.5	-	Ω	
Turn-on delay time	t <sub>d(on)</sub>		-	19	-		
Rise time	t <sub>r</sub>	$V_{DD} = 30 \text{ V}, R_{L} = 3.45 \Omega$	-	40	-		
Turn-off delay time	t <sub>d(off)</sub>	$I_D \cong 6.0 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$	-	18	-	1	
Fall time	t <sub>f</sub>		-	31	-		
Turn-on delay time	t <sub>d(on)</sub>		-	10	-	ns	
Rise time	t <sub>r</sub>	$V_{DD} = 30 \text{ V}, R_{L} = 3.45 \Omega$	-	26	-	- - -	
Turn-off delay time	t <sub>d(off)</sub>	$I_D \cong 8.0 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	-	11	-		
Fall time	t <sub>f</sub>		-	19	-		
<b>Drain-Source Body Diode Characteristics</b>	•			<u> </u>			
Continuous source-drain diode Current	Is	T <sub>C</sub> = 25 °C	-	-	12		
Pulse diode forward current <sup>a</sup>	I <sub>SM</sub>		-	-	48	A	
Body diode voltage	V <sub>SD</sub>	I <sub>S</sub> = 8.0 A	-	0.7	1.2	V	
Body diode reverse recovery time	t <sub>rr</sub>	<u> </u>		35	55	ns	
Body diode reverse recovery charge	Q <sub>rr</sub>	$I_F = 8.7 \text{ A}, \text{ di/dt} = 100 \text{ A/µs},$	_	32	40	nC	
Reverse recovery fall time	t <sub>a</sub>	$T_{\text{J}} = 25  ^{\circ}\text{C}$	-	11	-		
Reverse recovery rise time	t <sub>b</sub>	1		18	_	ns	

#### Notes

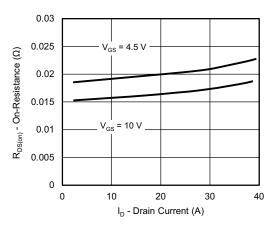
- a. Guaranteed by design, not subject to production testing
- b. Pulse test; pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2 %

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

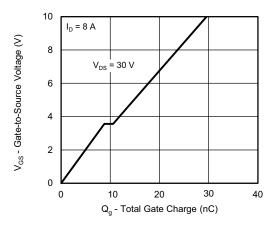




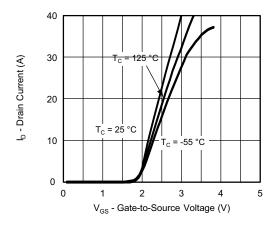
#### **Output Characteristics**



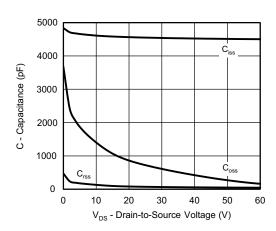
On-Resistance vs. Drain Current



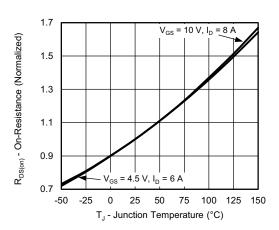
**Gate Charge** 



**Transfer Characteristics** 

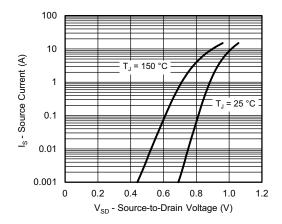


Capacitance

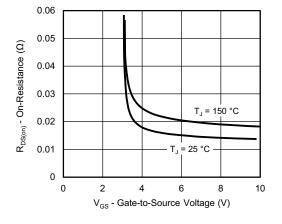


On-Resistance vs. Junction Temperature

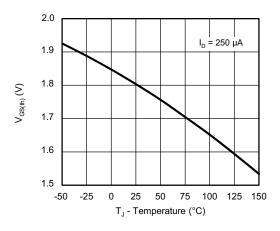




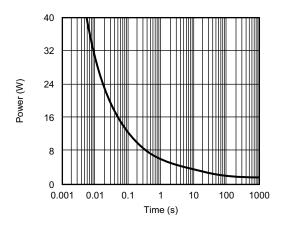
Source-Drain Diode Forward Voltage



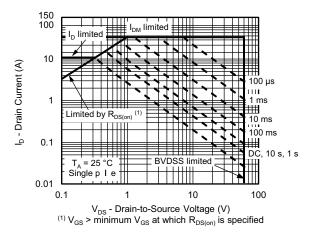
On-Resi.0stance vs. Gate-to-Source Voltage



**Threshold Voltage** 

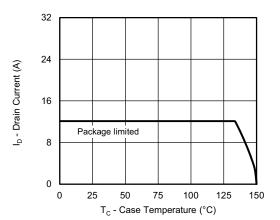


Single Pulse Power

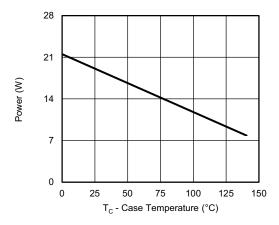


Safe Operating Area, Junction-to-Ambient

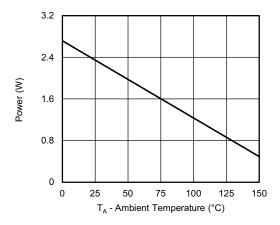




#### Current Derating a



Power, Junction-to-Case

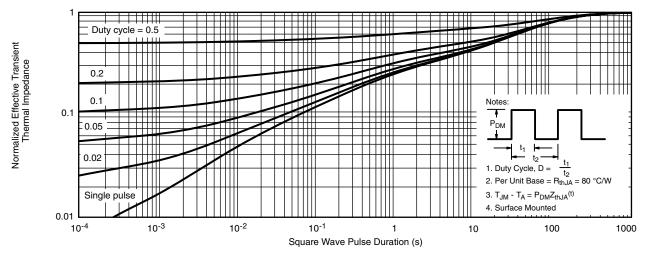


Power, Junction-to-Ambient

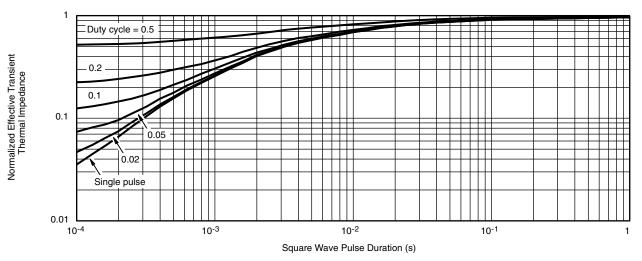
#### Note

a. The power dissipation  $P_D$  is based on  $T_J$  max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case





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